

SID4-HR

WAVE FRONT SENSOR



↓ SPECIFICATIONS

Aperture dimension	8,9 x 11,8 mm ²
Spatial resolution	29,6 μm
Sampling	300 x 400 (>120 000 points)
Wavelength range	400 - 1100 nm
Accuracy (absolute)	10 nm
Sensitivity	2 nm
Dynamic	> 500 μm
Radius of curvature	2 mm to +∞ (standard 20 mm)
Sensitivity curvature measurement	1. 10 ⁻³ m ⁻¹
Analysis rate	3 fps
Acquisition rate	10 fps
Dimensions (l x H x L)	76 x 63 x 132 mm
Weight	620 g

→ SID4-High Resolution

wave front sensor is adapted for optical metrology needs. It associates the SID4 ease of implementation with ultra high resolution. The SID4-HR gives an instantaneous measurement on the whole object to characterize.

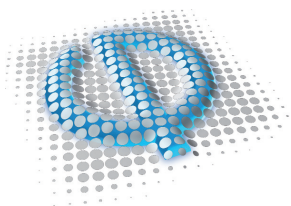
It is optimized to **surface inspection** (roughness, high frequency defects...) and **optical components characterization** (lens, objective, aspheric...).

The high performance camera increases the precision for laser characterization.

The 300 x 400 phase map sampling with such compactness make the SID4-HR a unique tool for optics and laser in research and industry.

→ KEY FEATURES

- Very high resolution (400 x 300)
- Large analysis pupil (8,9 mm x 11,8 mm)
- High dynamic range
- Instantaneous measurement on a large field
- Optimal signal to noise ratio
- Compactness for easy implementation



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